PDF/SOLUTIONS™

Unique and Robust Semiconductor Characterization Capabilities

Overview

PDF Solutions is the acknowledged commercial leader in parametric characterization systems, pioneering the use of short-flow test chips for developing and ramping new technologies and products. Our CV test chips are proven to represent the process-layout interactions critical to validate and monitor for high-yielding, stable production.

Each CV test chip benefits from our decades of industry experience, customized for your product design style and/or process technology The CV® System is now also available on a subscription basis

Accelerate Time-to-Market By Up To 3 Months

The CV System provides differentiated parametric electrical data, and when combined with the Exensio® Analytics Platform, delivers actionable insights that significantly shorten design iterations and accelerates time-to-market by up to three months.

A complete system for characterization

The CV System is the combination of high-density CV test chip layouts targeted to our proprietary pdFasTest® parallel parametric tester, producing data 100x faster than conventional test chip systems with automatic ingestion into the Exensio® Analytics Platform.
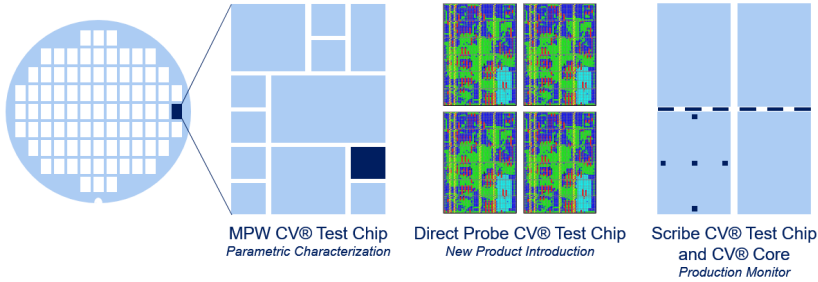
The CV System includes sub-PPB (parts-per-billion) statistical resolution, a broad layout pattern Design-of-Experiments (DoE), area efficiency, and automated analysis. 100% test and analysis of an entire lot of a full-reticle CV can be completed in less than a day.

Product Highlights

- The industry's leading system for parametric characterization

- Up to 100x faster than conventional test systems

- Up to 30x denser structures

- Up to 10x faster analysis

- Over 100 test chips at 10nm and below
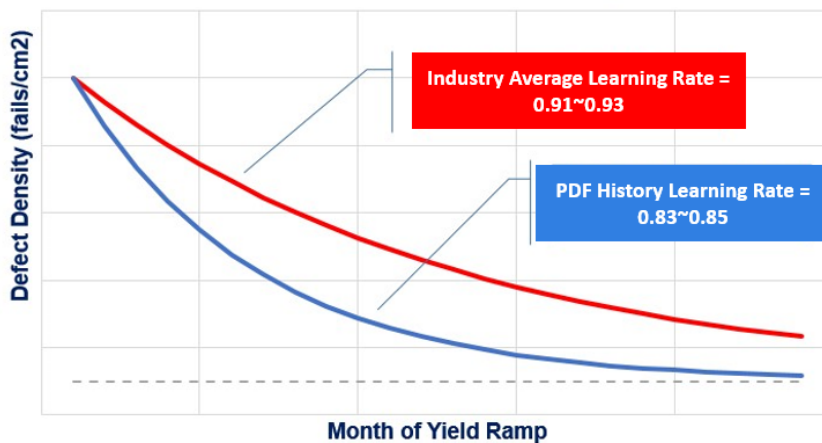
- Shortens TTM by up to 3 months

Characterization Vehicle® System

CV System for Fabless

MPW CV® Test Chip	Direct Probe CV® Test Chip	Scribe CV® Test Chip and CV® Core
Parametric Characterization	*New Product Introduction*	*Production Monitor*

First-time-right product tape-outs are critical for business success. Stable mass production is necessary for WIP optimization and profits. The CV System for fabless provides the parametric insight to help achieve your objectives.

CV System for Foundries and IDMs

Industry Average Learning Rate = 0.91~0.93

PDF History Learning Rate = 0.83~0.85

For over two decades, PDF Solutions has helped foundries and IDM's achieve world-class learning rates for technology development and mass production ramp.

Robustness & Predictability in Volume Manufacturing

Product Yield vs. CV Test Chip Response

CV System for Fabless Semiconductor Companies

- **MPW (mass production wafer) CV** provides the insight to uncover functional and parametric issues before mass production

- **Direct Probe CV provides the insight to find functional and parametric issues during NPI (new product introduction)**

- **Scribe CV and CV Core IP provides monitoring and rapid diagnosis capability to achieve high-quality mass production at optimized cost**

For more information about the CV System for Fabless, contact your local sales representative

Exensio visualizations Powered by TIBCO®

PDF/SOLUTIONS™

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